

NCV4269C

LDO Linear Regulator - **Micropower, DELAY, Adjustable RESET, Sense Output**

5.0 V, 150 mA

The NCV4269C is a 5.0 V precision micropower voltage regulator with an output current capability of 150 mA.

The output voltage is accurate within $\pm 2.0\%$ with a maximum dropout voltage of 0.5 V at 100 mA. Low quiescent current is a feature drawing only 125 μ A with a 1.0 mA load. This part is ideal for any and all battery operated microprocessor equipment.

Microprocessor control logic includes an active reset output RO with delay and a SI/SO monitor which can be used to provide an early warning signal to the microprocessor of a potential impending reset signal. The use of the SI/SO monitor allows the microprocessor to finish any signal processing before the reset shuts the microprocessor down.

The active Reset circuit operates correctly at an output voltage as low as 1.0 V. The Reset function is activated during the power up sequence or during normal operation if the output voltage drops outside the regulation limits.

The reset threshold voltage can be decreased by the connection of an external resistor divider to the R_{ADJ} lead. The regulator is protected against reverse battery, short circuit, and thermal overload conditions. The device can withstand load dump transients making it suitable for use in automotive environments. The device has also been optimized for EMC conditions.

Features

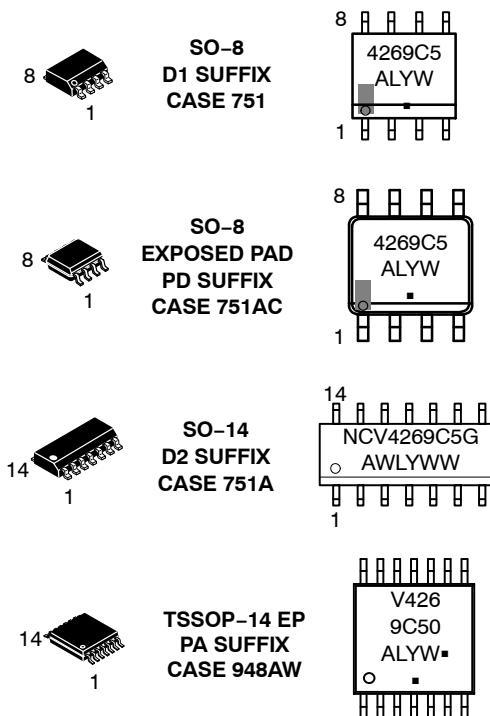
- 5.0 V $\pm 2.0\%$ Output
- Low 125 μ A Quiescent Current
- Active Reset Output Low Down to $V_Q = 1.0$ V
- Adjustable Reset Threshold
- 150 mA Output Current Capability
- Fault Protection
 - ◆ +60 V Peak Transient Voltage
 - ◆ -40 V Reverse Voltage
 - ◆ Short Circuit
 - ◆ Thermal Overload
- Early Warning through SI/SO Leads
- Internally Fused Leads in SO-14 Package
- Integrated Pullup Resistor at Logic Outputs (To Use External Resistors, Select the NCV4279C)
- Very Low Dropout Voltage
- Electrical Parameters Guaranteed Over Entire Temperature Range
- AEC-Q100 Grade 1 Qualified and PPAP Capable
- These are Pb-Free Devices



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MARKING DIAGRAM



A = Assembly Location

WL, L = Wafer Lot

Y = Year

WW, W = Work Week

G, ■ = Pb Free

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 13 of this data sheet.

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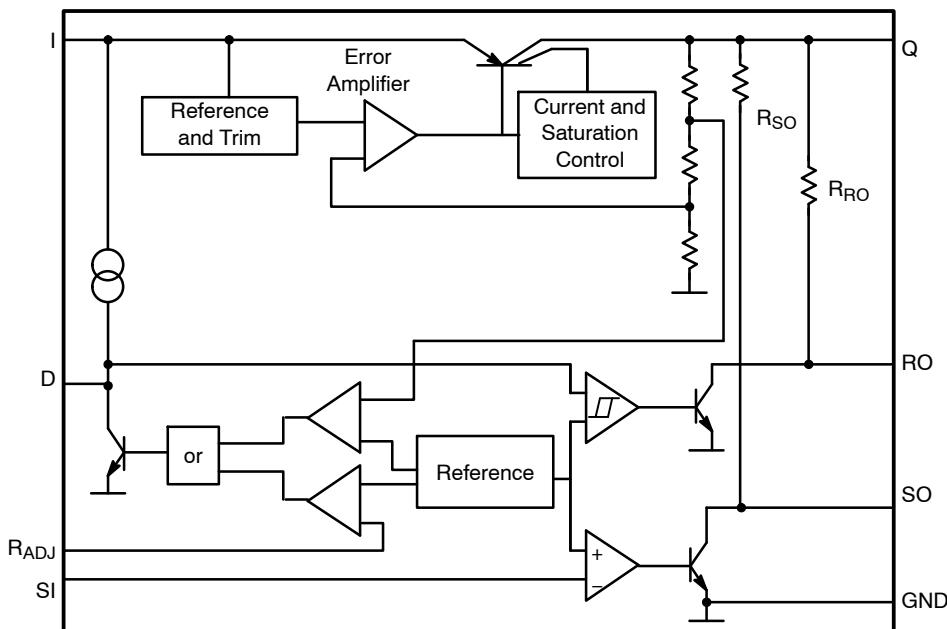
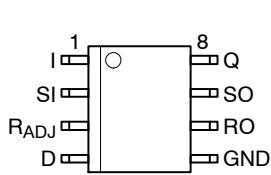
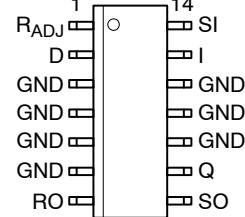


Figure 1. Block Diagram

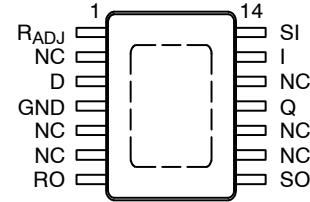
PIN CONNECTIONS



SO-8



SO-14



TSSOP-14 EP

PACKAGE PIN DESCRIPTION

Package Pin Number				Pin Symbol	Function
SO-8	SO-8 EP	SO-14	TSSOP14		
3	3	1	1	R _{ADJ}	Reset Threshold Adjust; if not used to connect to GND.
4	4	2	3	D	Reset Delay; To Set Time Delay, Connect to GND with Capacitor
5	5	3, 4, 5, 6, 10, 11, 12	4	GND	Ground
-	-	-	2, 5, 6, 9, 10, 12	NC	No connection to these pins from the IC.
6	6	7	7	RO	Reset Output; The Open-Collector Output has a 20 kΩ Pullup Resistor to Q. Leave Open if Not Used.
7	7	8	8	SO	Sense Output; This Open-Collector Output is Internally Pulled Up by 20 kΩ pullup resistor to Q. If not used, keep open.
8	8	9	11	Q	5 V Output; Connect to GND with a 10 µF Capacitor, ESR < 2.5 Ω.
1	1	13	13	I	Input; Connect to GND Directly at the IC with Ceramic Capacitor.
2	2	14	14	SI	Sense Input; If not used, Connect to Q.
-	EPAD	-	EPAD	EPAD	Connect to ground potential or leave unconnected

MAXIMUM RATINGS ($T_J = -40^{\circ}\text{C}$ to 150°C)

Parameter	Symbol	Min	Max	Unit
Input to Regulator	V_I I_I	-40 Internally Limited	45 Internally Limited	V
Input Transient to Regulator (Note 3)	V_I	-	60	V
Sense Input	V_{SI} I_{SI}	-40 -1	45 1	V mA
Reset Threshold Adjust	V_{RADJ} I_{RADJ}	-0.3 -10	7 10	V mA
Reset Delay	V_D I_D	-0.3 Internally Limited	7 Internally Limited	V
Ground	I_q	50	-	mA
Reset Output	V_{RO} I_{RO}	-0.3 Internally Limited	7 Internally Limited	V
Sense Output	V_{SO} I_{SO}	-0.3 Internally Limited	7 Internally Limited	V
Regulated Output	V_Q I_Q	-0.5 -10	7 -	V mA
Junction Temperature Storage Temperature	T_J T_{STG}	- -50	150 150	°C °C
Input Voltage Operating Range Junction Temperature Operating Range	V_I T_J	- -40	45 150	V °C

LEAD TEMPERATURE SOLDERING AND MSL

Parameter	Symbol	Value
MSL, 8-Lead, 14-Lead, LS Temperature 265°C Peak (Note 4)	MSL	1
MSL, 8-Lead EP, LS Temperature 260°C	MSL	2

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. This device series incorporates ESD protection and exceeds the following ratings:

Human Body Model (HBM) $\leq 4.0 \text{ kV}$ per AEC-Q100-002.

Machine Model (MM) $\leq 200 \text{ V}$ per AEC-Q100-003.

2. Latchup tested per AEC-Q100-004.

3. Load Dump Test B (with centralized load dump suppression) according to ISO16750-2 standard. Guaranteed by design. Not tested in production. Passed Class A according to ISO16750-1.

4. $+5^{\circ}\text{C}/-0^{\circ}\text{C}$, 40 Sec Max-at-Peak, 60 – 150 Sec above 217°C .

THERMAL CHARACTERISTICS

Characteristic	Test Conditions (Typical Values)	Unit
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SO-8 Package (Note 5)

Junction-to-Pin 6 ($\Psi - JL6, \Psi_{L6}$)	58.3	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA}, \theta_{JA}$)	151.1	°C/W

SO-8 EP Package (Note 5)

Junction-to-Pin 8 ($\Psi - JL8, \Psi_{L8}$)	47	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA}, \theta_{JA}$)	131.6	°C/W
Junction-to-Pad ($\Psi - JPad$)	16.3	°C/W

SO-14 Package (Note 5)

Junction-to-Pin 4 ($\Psi - JL4, \Psi_{L4}$)	19.5	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA}, \theta_{JA}$)	100.9	°C/W

TSSOP-14 EP Package (Note 5)

Junction-to-Pin 3 ($\Psi - JL3, \Psi_{L3}$)	19.3	°C/W
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THERMAL CHARACTERISTICS

Characteristic	Test Conditions (Typical Values)	Unit
TSSOP-14 EP Package (Note 5)		
Junction-to-Ambient Thermal Resistance ($R_{\theta JA}$, θ_{JA})	77.3	°C/W
Junction-to-Pad (Ψ – JPad)	12.6	°C/W

5. 2 oz copper, 150 mm² copper area, 1.5 mm thick FR4

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ELECTRICAL CHARACTERISTICS ($T_J = -40^\circ\text{C} \leq T_J \leq 150^\circ\text{C}$, $V_I = 13.5\text{ V}$ unless otherwise specified)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
REGULATOR						
Output Voltage	V_Q	$1\text{ mA} \leq I_Q \leq 100\text{ mA}$ $6\text{ V} \leq V_I \leq 16\text{ V}$	4.90	5.00	5.10	V
Current Limit	I_Q	–	150	430	500	mA
Current Consumption; $I_q = I_I - I_Q$	I_q	$I_Q = 1\text{ mA}$, RO, SO High	–	125	250	μA
Current Consumption; $I_q = I_I - I_Q$	I_q	$I_Q = 10\text{ mA}$, RO, SO High	–	230	450	μA
Current Consumption; $I_q = I_I - I_Q$	I_q	$I_Q = 50\text{ mA}$, RO, SO High	–	0.9	3.0	mA
Dropout Voltage	V_{dr}	$V_I = 5\text{ V}$, $I_Q = 100\text{ mA}$	–	0.23	0.5	V
Load Regulation	ΔV_Q	$I_Q = 5\text{ mA}$ to 100 mA	–	1	20	mV
Line Regulation	ΔV_Q	$V_I = 6\text{ V}$ to 26 V $I_Q = 1\text{ mA}$	–	1	30	mV

RESET GENERATOR

Reset Switching Threshold	V_{RT}	–	4.50	4.65	4.80	V
Reset Adjust Switching Threshold	$V_{RADJ,TH}$	$V_Q > 3.5\text{ V}$	1.26	1.35	1.44	V
Reset Pullup Resistance	$R_{RO,INT}$	–	10	20	40	$\text{k}\Omega$
Reset Output Saturation Voltage	$V_{RO,SAT}$	$V_Q < V_{RT}$, $R_{RO, INT}$	–	0.03	0.4	V
Upper Delay Switching Threshold	V_{UD}	–	1.4	1.8	2.2	V
Lower Delay Switching Threshold	V_{LD}	–	0.3	0.45	0.60	V
Saturation Voltage on Delay Capacitor	$V_{D,SAT}$	$V_Q < V_{RT}$	–	–	0.1	V
Charge Current	$I_{D,C}$	$V_D = 1\text{ V}$	3.0	6.5	9.5	μA
Delay Time L → H	t_d	$C_D = 100\text{ nF}$	17	28	73	ms
Delay Time H → L	t_{RR}	$C_D = 100\text{ nF}$	–	1.5	–	μs

INPUT VOLTAGE SENSE

Sense Threshold High	$V_{SI,High}$	–	1.24	1.31	1.38	V
Sense Threshold Low	$V_{SI,Low}$	–	1.16	1.20	1.28	V
Sense Output Saturation Voltage	$V_{SO,Low}$	$V_{SI} < 1.20\text{ V}$; $V_Q > 3\text{ V}$; $R_{SO,INT}$	–	0.03	0.4	V
Sense Resistor Pullup	$R_{SO,INT}$	–	10	20	40	$\text{k}\Omega$
Sense Input Current	I_{SI}	–	-1.0	0.1	1.0	μA

THERMAL SHUTDOWN

Thermal Shutdown Temperature (Note 6)	T_{SD}	$I_{out} = 1\text{ mA}$	150	–	200	$^\circ\text{C}$
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Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Values based on design and/or characterization.

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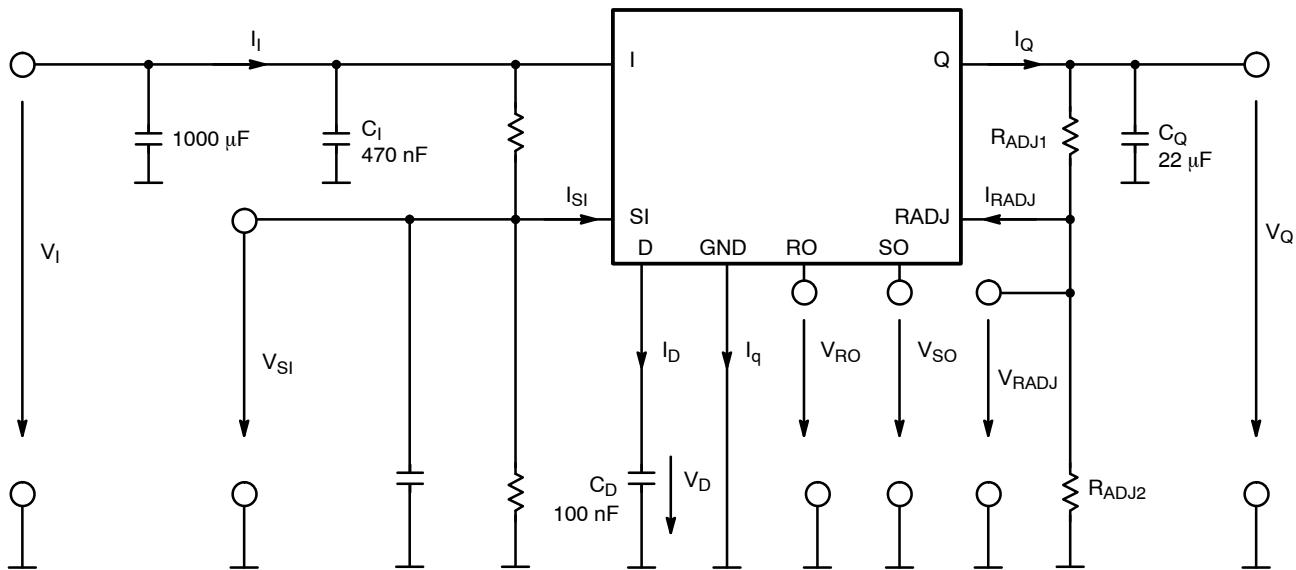


Figure 2. Measuring Circuit

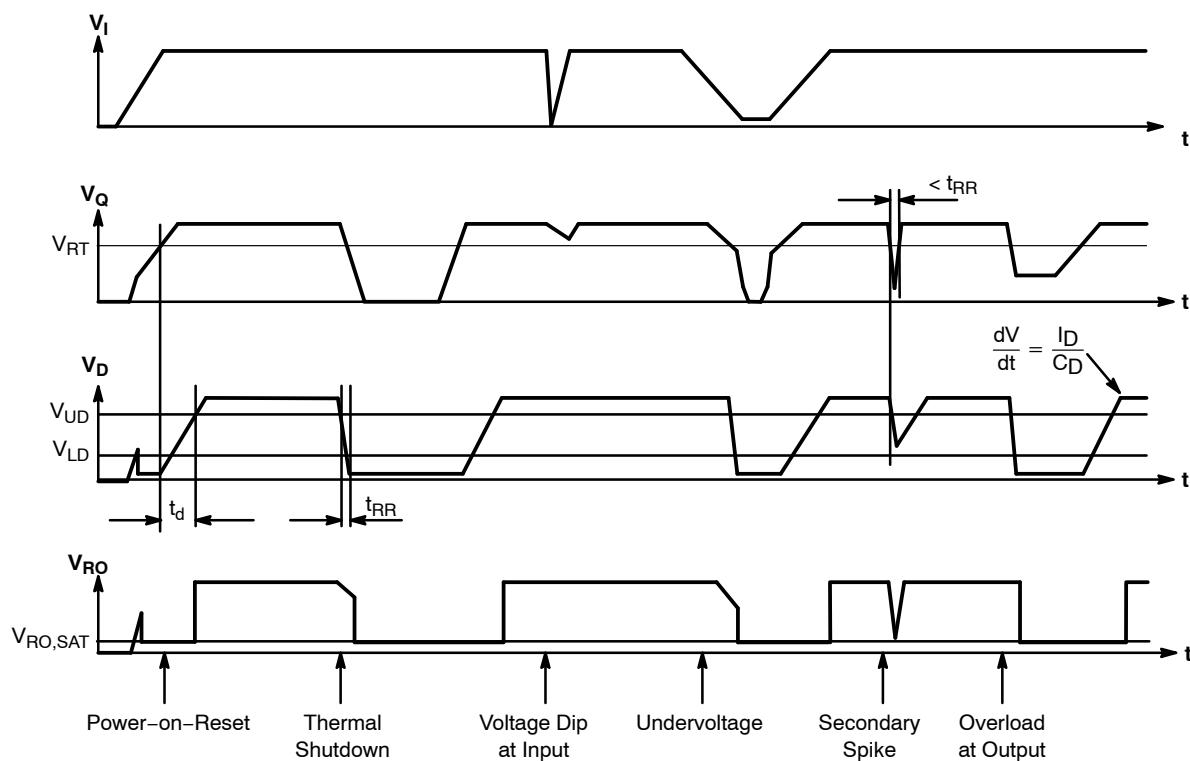


Figure 3. Reset Timing Diagram

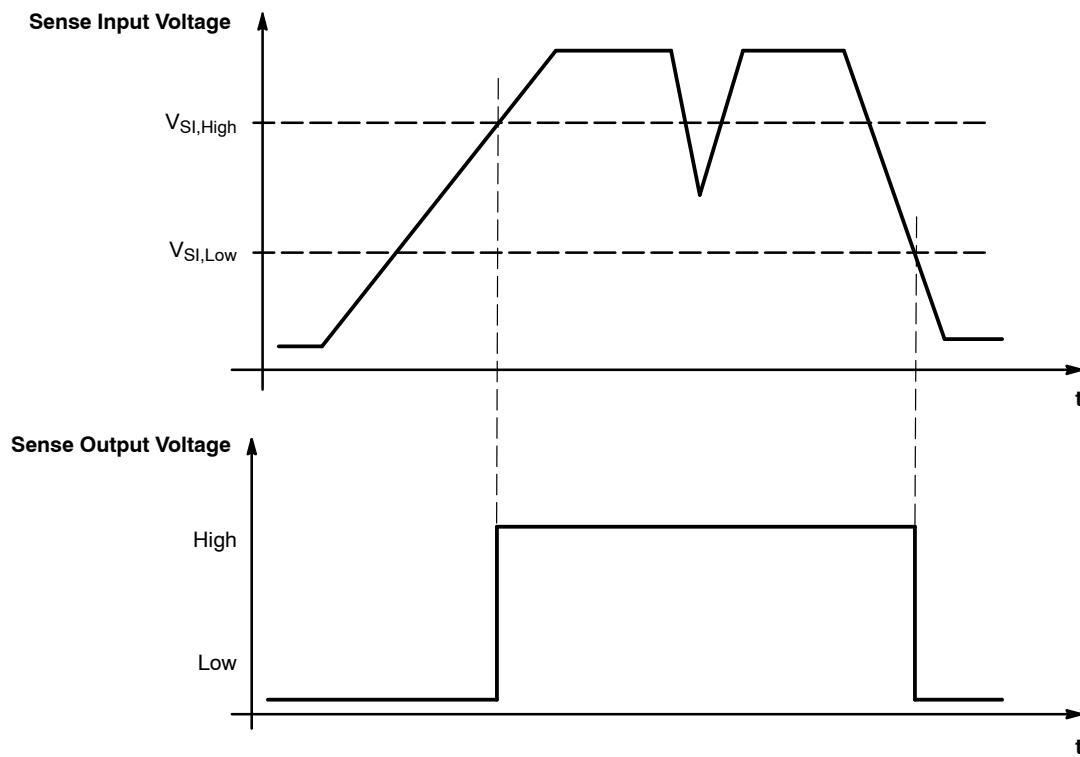


Figure 4. Sense Timing Diagram

TYPICAL PERFORMANCE CHARACTERISTICS

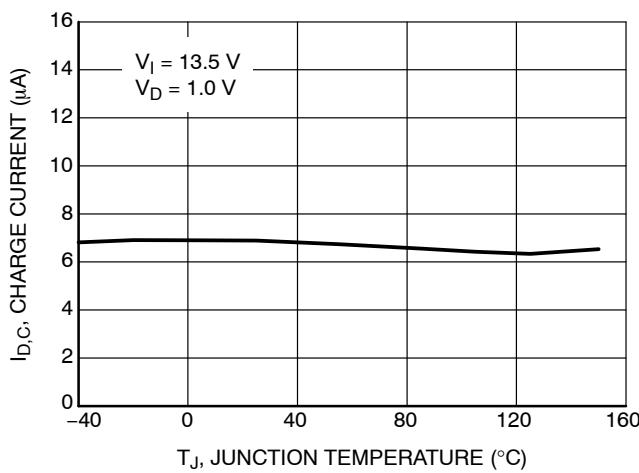


Figure 5. Charge Current $I_{D,C}$ vs. Temperature T_J

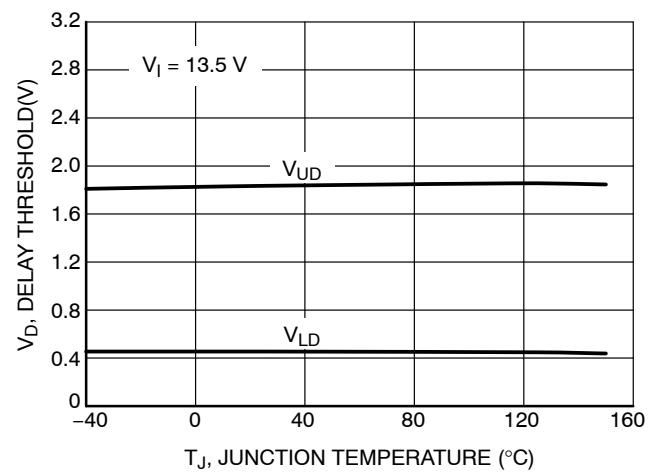
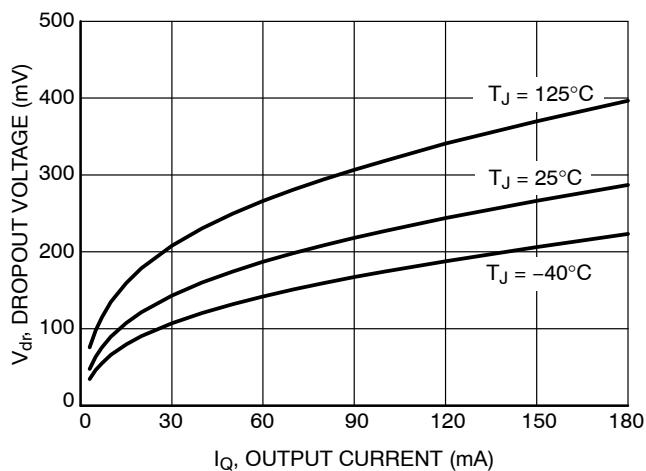
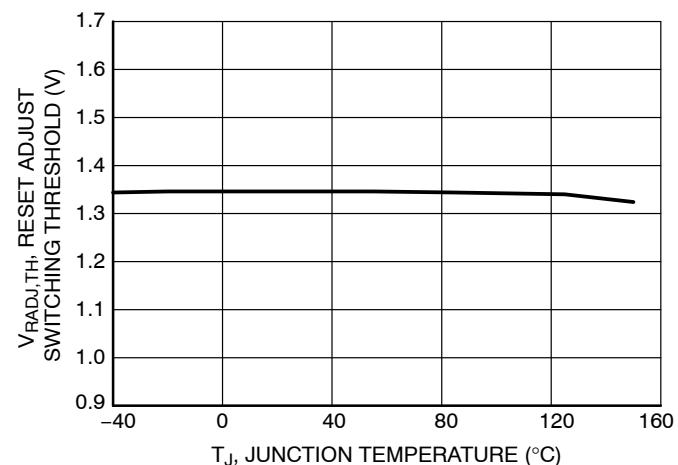
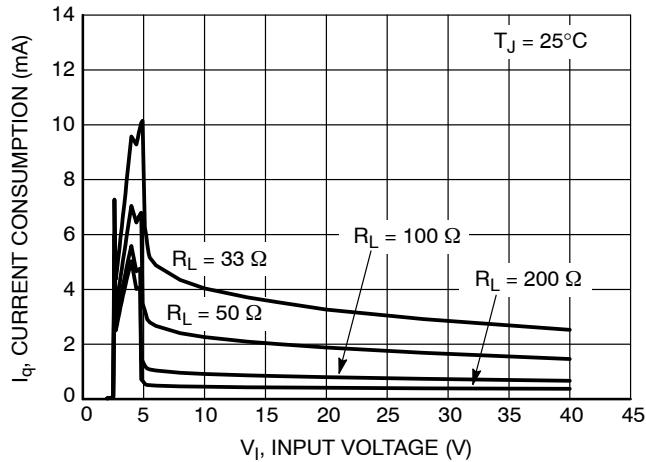
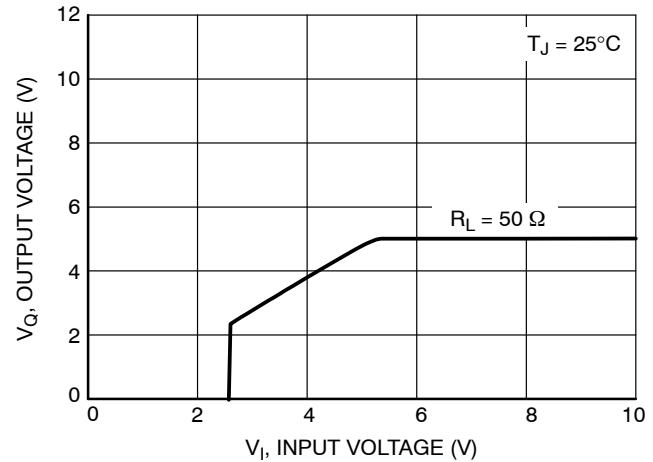
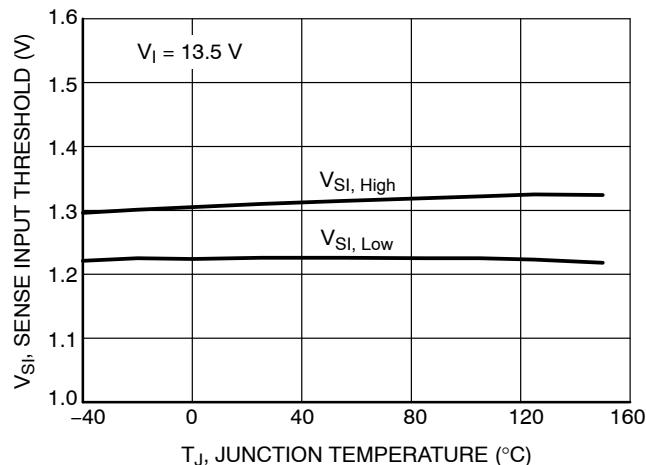
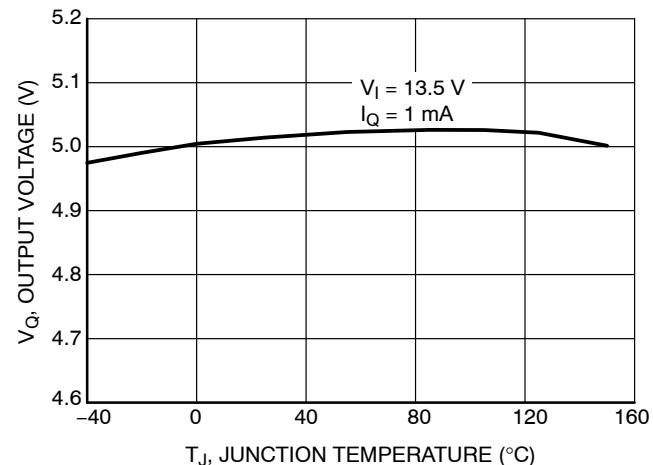


Figure 6. Switching Voltage V_{UD} and V_{LD} vs. Temperature T_J

TYPICAL PERFORMANCE CHARACTERISTICS

Figure 7. Drop Voltage V_{dR} vs. Output Current I_Q Figure 8. Reset Adjust Switching Threshold, $V_{RADJ,TH}$ vs. Temperature T_J Figure 9. Current Consumption I_Q vs. Input Voltage V_I Figure 10. Output Voltage V_Q vs. Input Voltage V_I Figure 11. Sense Threshold V_{SI} vs. Temperature T_J Figure 12. Output Voltage V_Q vs. Temperature T_J

TYPICAL PERFORMANCE CHARACTERISTICS

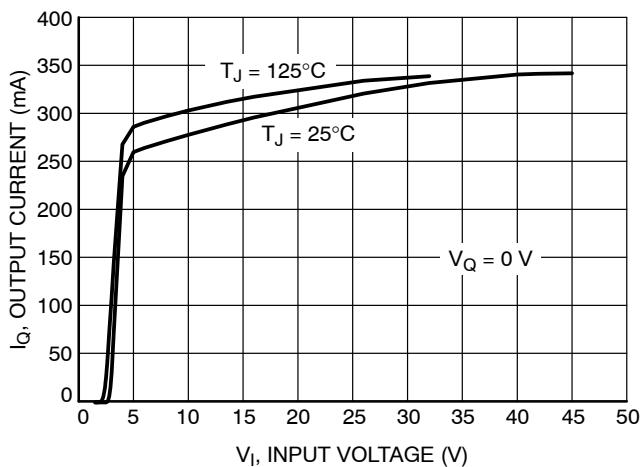
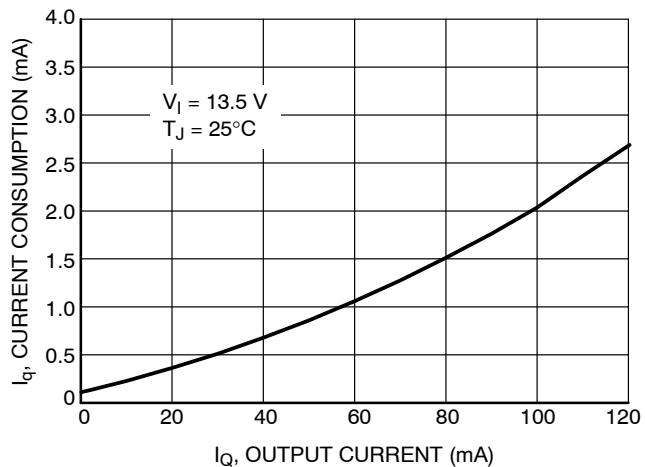
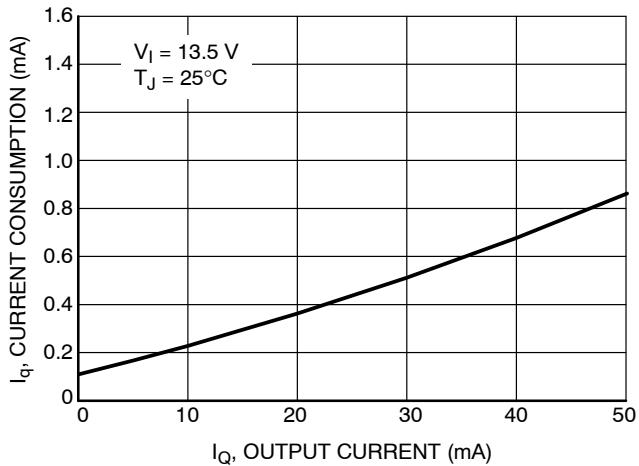
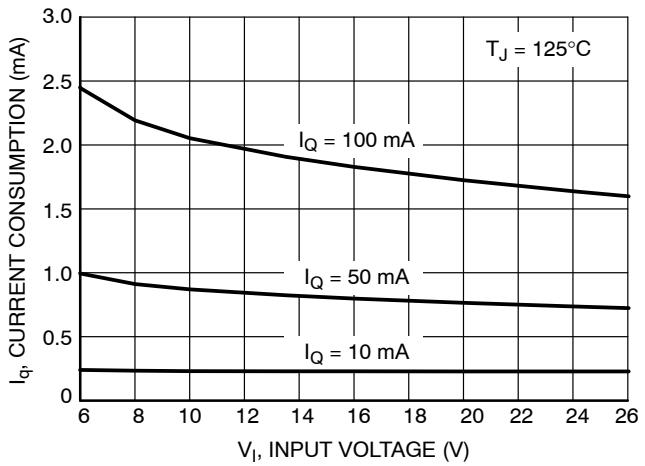
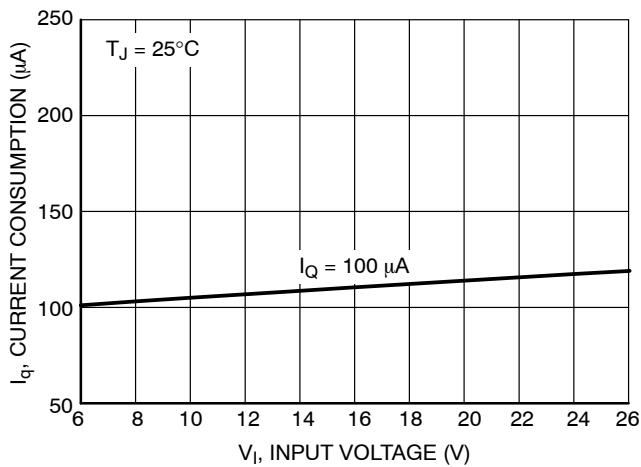
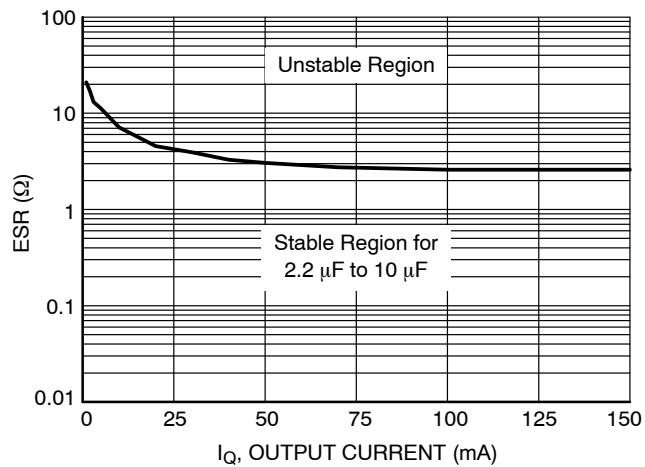
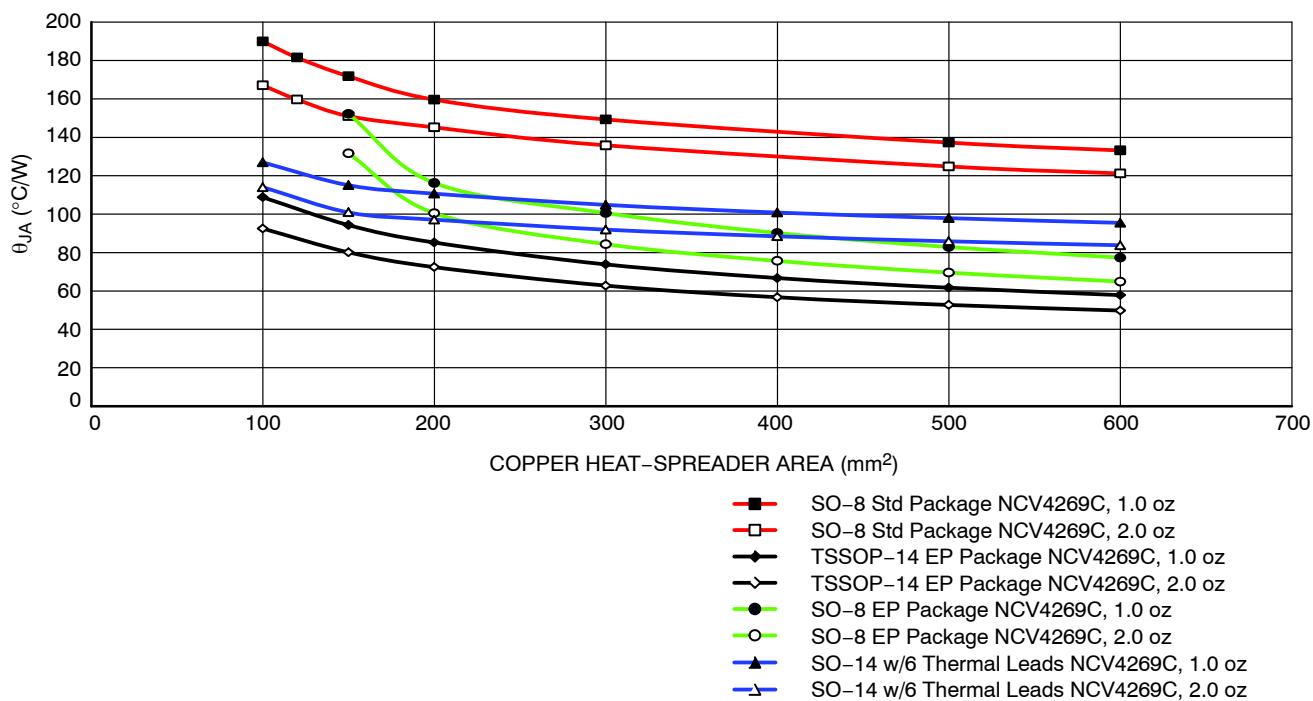
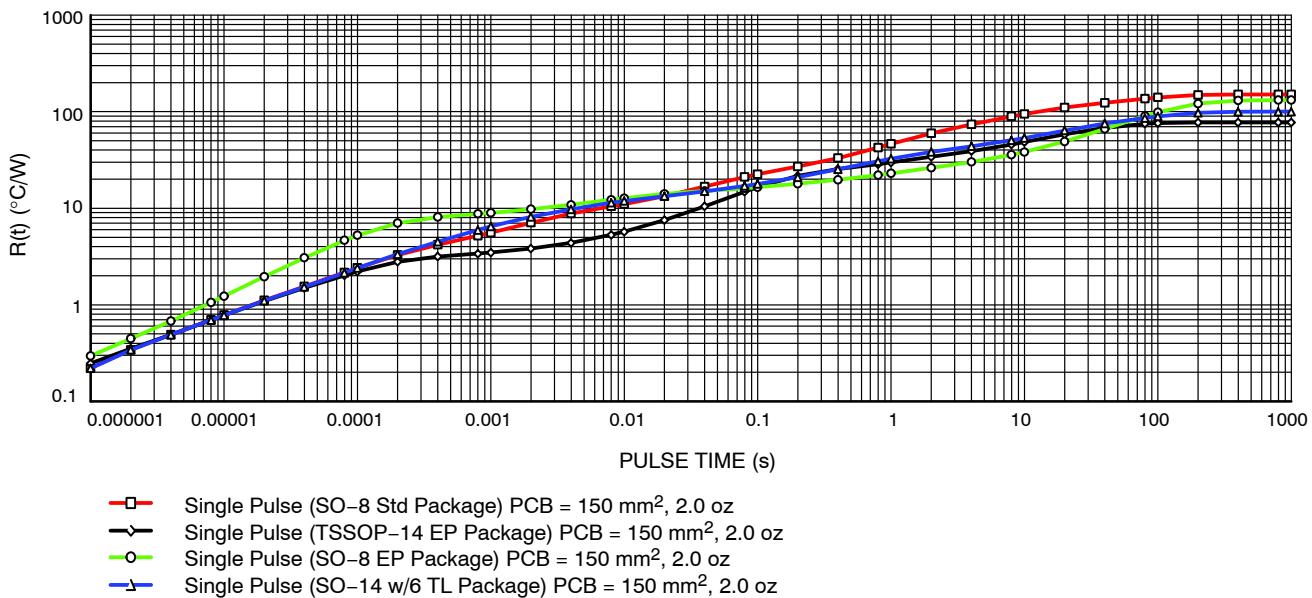
Figure 13. Output Current I_Q vs. Input Voltage V_I Figure 14. Current Consumption I_q vs. Output Current I_Q Figure 15. Current Consumption I_q vs. Output Current I_Q Figure 16. Quiescent Current I_q vs. Input Voltage V_I Figure 17. Quiescent Current I_q vs. Input Voltage V_I 

Figure 18. Output Stability, Capacitance ESR vs. Output Load Current

TYPICAL THERMAL CHARACTERISTICS

Figure 19. Junction-to-Ambient Thermal Resistance (θ_{JA}) vs. Heat Spreader AreaFigure 20. $R(t)$ vs. Pulse Time

APPLICATION DESCRIPTION

OUTPUT REGULATOR

The output is controlled by a precision trimmed reference. The PNP output has base drive quiescent current control for regulation while the input voltage is low, preventing over saturation. Current limit and voltage monitors complement the regulator design to give safe operating signals to the processor and control circuits.

RESET OUTPUT (RO)

A reset signal, Reset Output, RO, (low voltage) is generated as the IC powers up. After the output voltage V_Q increases above the reset threshold voltage V_{RT} , the delay timer D is started. When the voltage on the delay timer V_D passes V_{UD} , the reset signal RO goes high. A discharge of the delay timer V_D is started when V_Q drops and stays below the reset threshold voltage V_{RT} . When the voltage of the delay timer V_D drops below the lower threshold voltage V_{LD} the reset output voltage V_{RO} is brought low to reset the processor.

The reset output RO is an open collector NPN transistor with an internal 20 k Ω pullup resistor connected to the output Q, controlled by a low voltage detection circuit. The circuit is functionally independent of the rest of the IC, thereby guaranteeing that RO is valid for V_Q as low as 1.0 V.

RESET ADJUST (R_{ADJ})

The reset threshold V_{RT} can be decreased from a typical value of 4.65 V to as low as 3.5 V by using an external voltage divider connected from the Q lead to the pin R_{ADJ}, as shown in Figure 21. The resistor divider keeps the voltage above the $V_{RADJ,TH}$ (typical 1.35 V) for the desired input voltages, and overrides the internal threshold detector. Adjust the voltage divider according to the following relationship:

$$V_{RT} = V_{RADJ, TH} \cdot (R_{ADJ1} + R_{ADJ2}) / R_{ADJ2} \quad (\text{eq. 1})$$

If the reset adjust option is not needed, the R_{ADJ} pin should be connected to GND causing the reset threshold to go to its default value (typically 4.65 V).

RESET DELAY (D)

The reset delay circuit provides a delay (programmable by capacitor C_D) on the reset output lead RO. The delay lead D provides charge current I_{D,C} (typically 6.5 μ A) to the external delay capacitor C_D during the following times:

1. During Powerup (once the regulation threshold has been exceeded).
2. After a reset event has occurred and the device is back in regulation. The delay capacitor is set to discharge when the regulation (V_{RT}, reset threshold voltage) has been violated. When the delay capacitor discharges to V_{LD}, the reset signal RO pulls low.

SETTING THE DELAY TIME

The delay time is set by the delay capacitor C_D and the charge current I_D. The time is measured by the delay capacitor voltage charging from the low level of V_{DSAT} to the higher level V_{UD}. The time delay follows the equation:

$$t_d = [C_D (V_{UD} - V_{D,SAT})] / I_{D,C} \quad (\text{eq. 2})$$

Example:

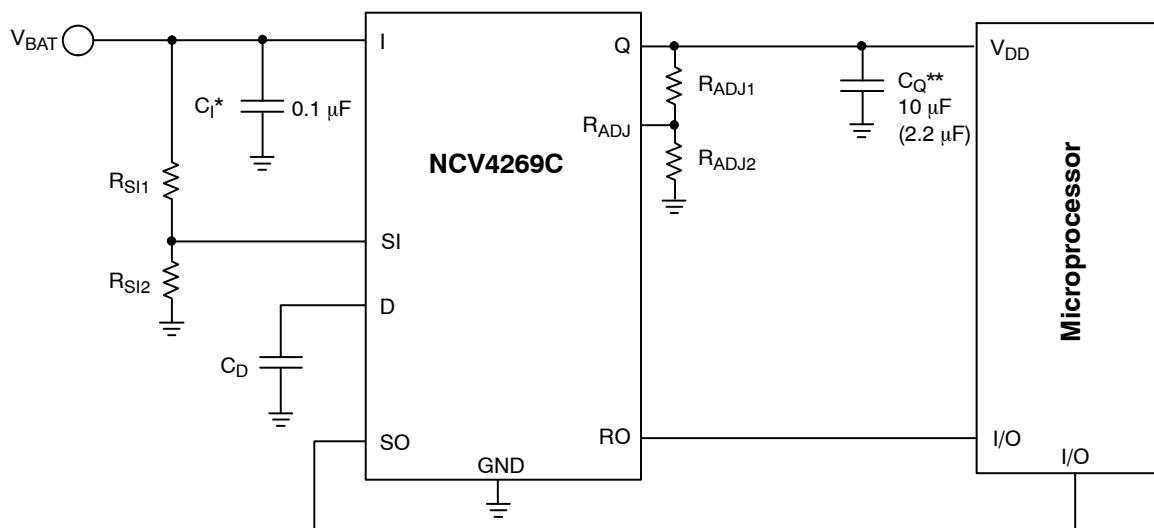
Using C_D = 100 nF.

Use the typical value for V_{D,SAT} = 0.1 V.

Use the typical value for V_{UD} = 1.8 V.

Use the typical value for Delay Charge Current I_D = 6.5 μ A.

$$t_d = [100 \text{ nF} (1.8 - 0.1 \text{ V})] / 6.5 \mu\text{A} = 26.2 \text{ ms} \quad (\text{eq. 3})$$



*C_I required if regulator is located far from the power supply filter.

** C_Q – minimum cap required for stability is 2.2 μ F while higher over/under-shoots may be expected. Cap must operate at minimum temperature expected.

Figure 21. Application Diagram

SENSE INPUT (SI) / SENSE OUTPUT (SO) VOLTAGE MONITOR

An on-chip comparator is available to provide early warning to the microprocessor of a possible reset signal (Figure 4). The output is from an open collector driver with an internal $20\text{ k}\Omega$ pull up resistor to output Q. The reset signal typically turns the microprocessor off instantaneously. This can cause unpredictable results with the microprocessor. The signal received from the SO pin will allow the microprocessor time to complete its present task before shutting down. This function is performed by a comparator referenced to the band gap voltage. The actual trip point can be programmed externally using a resistor divider to the input monitor SI (Figure 21). The values for R_{SI1} and R_{SI2} are selected for a typical threshold of 1.20 V on the SI Pin.

SIGNAL OUTPUT

Figure 22 shows the SO Monitor timing waveforms as a result of the circuit depicted in Figure 21. As the output voltage (V_Q) falls, the monitor threshold ($V_{SI,Low}$) is crossed. This causes the voltage on the SO output to go low sending a warning signal to the microprocessor that a reset signal may occur in a short period of time. $T_{WARNING}$ is the time the microprocessor has to complete the function it is currently working on and get ready for the reset shutdown signal. When the voltage on the SO goes low and the RO stays high the current consumption is typically 530 μA at 1 mA load current.

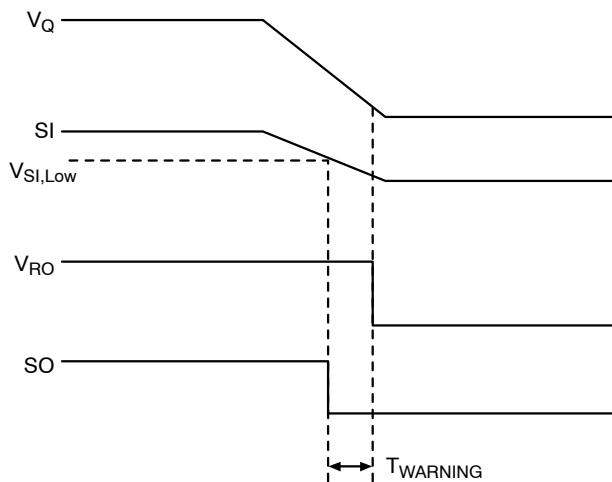


Figure 22. SO Warning Waveform Time Diagram

STABILITY CONSIDERATIONS

The input capacitor C_I in Figure 21 is necessary for compensating input line reactance. Possible oscillations caused by input inductance and input capacitance can be damped by using a resistor of approximately $1.0\text{ }\Omega$ in series with C_I .

The output or compensation capacitor helps determine three main characteristics of a linear regulator: startup delay, load transient response and loop stability.

The capacitor value and type should be based on cost, availability, size and temperature constraints. The aluminum electrolytic capacitor is the least expensive solution, but, if the circuit operates at low temperatures

(-25°C to -40°C), both the value and ESR of the capacitor will vary considerably. The capacitor manufacturer's data sheet usually provides this information.

The $10\text{ }\mu\text{F}$ output capacitor C_Q shown in Figure 21 should work for most applications; however, it is not necessarily the optimized solution. Stability is guaranteed at C_Q is min $2.2\text{ }\mu\text{F}$ and max ESR is $2.5\text{ }\Omega$. There is no min ESR limit which was proved with MURATA's ceramic caps GRM31MR71A225KA01 (2.2 μF , 10 V, X7R, 1206) and GRM31CR71A106KA01 (10 μF , 10 V, X7R, 1206) directly soldered between output and ground pins.

CALCULATING POWER DISSIPATION IN A SINGLE OUTPUT LINEAR REGULATOR

The maximum power dissipation for a single output regulator (Figure 21) is:

$$P_{D(\max)} = [V_{I(\max)} - V_{Q(\min)}]I_{Q(\max)} + V_{I(\max)}I_q \quad (\text{eq. 4})$$

where:

$V_{I(\max)}$ is the maximum input voltage,

$V_{Q(\min)}$ is the minimum output voltage,

$I_{Q(\max)}$ is the maximum output current for the application, and I_q is the quiescent current the regulator consumes at $I_{Q(\max)}$.

Once the value of $P_{D(\max)}$ is known, the maximum permissible value of $R_{\theta JA}$ can be calculated:

$$R_{\theta JA} = (150^\circ\text{C} - T_A) / P_D \quad (\text{eq. 5})$$

The value of $R_{\theta JA}$ can then be compared with those in the package section of the data sheet. Those packages with $R_{\theta JA}$'s less than the calculated value in equation 2 will keep the die temperature below 150°C . In some cases, none of the packages will be sufficient to dissipate the heat generated by the IC, and an external heatsink will be required. The current flow and voltages are shown in the Measurement Circuit Diagram.

HEATSINKS

A heatsink effectively increases the surface area of the package to improve the flow of heat away from the IC and into the surrounding air.

Each material in the heat flow path between the IC and the outside environment will have a thermal resistance. Like series electrical resistances, these resistances are summed to determine the value of $R_{\theta JA}$:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CS} + R_{\theta SA} \quad (\text{eq. 6})$$

where:

$R_{\theta JC}$ = the junction-to-case thermal resistance,

$R_{\theta CS}$ = the case-to-heatsink thermal resistance, and

$R_{\theta SA}$ = the heatsink-to-ambient thermal resistance.

$R_{\theta JC}$ appears in the package section of the data sheet. Like $R_{\theta JA}$, it too is a function of package type. $R_{\theta CS}$ and $R_{\theta SA}$ are functions of the package type, heatsink and the interface between them. These values appear in data sheets of heatsink manufacturers. Thermal, mounting, and heatsinking considerations are discussed in the ON Semiconductor application note AN1040/D, available on the ON Semiconductor website.

NCV4269C

ORDERING INFORMATION

Device	Output Voltage	Package	Shipping [†]
NCV4269CD150R2G	5.0 V	SO-8 (Pb-Free)	2500 / Tape & Reel
NCV4269CPD50R2G		SO-8 EP (Pb-Free)	2500 / Tape & Reel
NCV4269CD250R2G		SO-14 (Pb-Free)	2500 / Tape & Reel
NCV4269CPA50R2G		TSSOP-14 (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

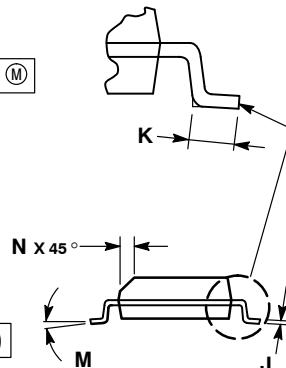
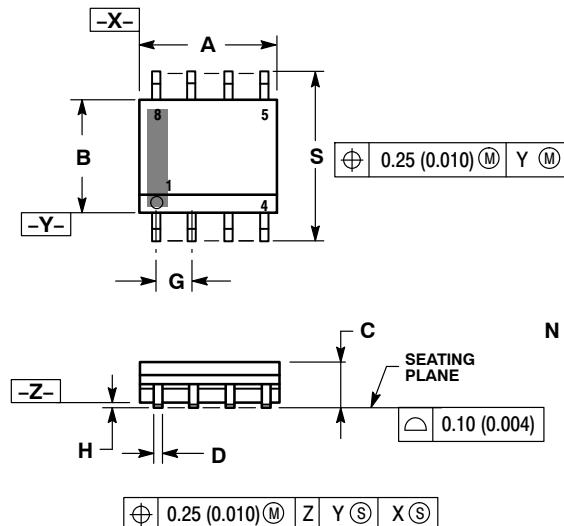
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SCALE 1:1

SOIC-8 NB
CASE 751-07
ISSUE AK

DATE 16 FEB 2011

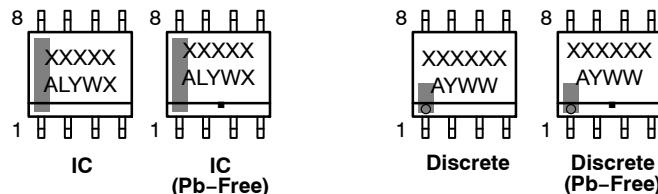


NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.80	5.00	0.189	0.197
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
H	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

**GENERIC
MARKING DIAGRAM***



XXXXX = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
▪ = Pb-Free Package

XXXXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
▪ = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

SCALE 6:1 (mm/inches)

STYLES ON PAGE 2

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SOIC-8 NB
CASE 751-07
ISSUE AK

DATE 16 FEB 2011

STYLE 1: PIN 1. Emitter 2. Collector 3. Collector 4. Emitter 5. Emitter 6. Base 7. Base 8. Emitter	STYLE 2: PIN 1. Collector, Die #1 2. Collector, #1 3. Collector, #2 4. Collector, #2 5. Base, #2 6. Emitter, #2 7. Base, #1 8. Emitter, #1	STYLE 3: PIN 1. Drain, Die #1 2. Drain, #1 3. Drain, #2 4. Drain, #2 5. Gate, #2 6. Source, #2 7. Gate, #1 8. Source, #1	STYLE 4: PIN 1. Anode 2. Anode 3. Anode 4. Anode 5. Anode 6. Anode 7. Anode 8. Common Cathode
STYLE 5: PIN 1. Drain 2. Drain 3. Drain 4. Drain 5. Gate 6. Gate 7. Source 8. Source	STYLE 6: PIN 1. Source 2. Drain 3. Drain 4. Source 5. Source 6. Gate 7. Gate 8. Source	STYLE 7: PIN 1. Input 2. External Bypass 3. Third Stage Source 4. Ground 5. Drain 6. Gate 3 7. Second Stage Vd 8. First Stage Vd	STYLE 8: PIN 1. Collector, Die #1 2. Base, #1 3. Base, #2 4. Collector, #2 5. Collector, #2 6. Emitter, #2 7. Emitter, #1 8. Collector, #1
STYLE 9: PIN 1. Emitter, Common 2. Collector, Die #1 3. Collector, Die #2 4. Emitter, Common 5. Emitter, Common 6. Base, Die #2 7. Base, Die #1 8. Emitter, Common	STYLE 10: PIN 1. Ground 2. Bias 1 3. Output 4. Ground 5. Ground 6. Bias 2 7. Input 8. Ground	STYLE 11: PIN 1. Source 1 2. Gate 1 3. Source 2 4. Gate 2 5. Drain 2 6. Drain 2 7. Drain 1 8. Drain 1	STYLE 12: PIN 1. Source 2. Source 3. Source 4. Gate 5. Drain 6. Drain 7. Drain 8. Drain
STYLE 13: PIN 1. N.C. 2. Source 3. Source 4. Gate 5. Drain 6. Drain 7. Drain 8. Drain	STYLE 14: PIN 1. N-Source 2. N-Gate 3. P-Source 4. P-Gate 5. P-Drain 6. P-Drain 7. N-Drain 8. N-Drain	STYLE 15: PIN 1. Anode 1 2. Anode 1 3. Anode 1 4. Anode 1 5. Cathode, Common 6. Cathode, Common 7. Cathode, Common 8. Cathode, Common	STYLE 16: PIN 1. Emitter, Die #1 2. Base, Die #1 3. Emitter, Die #2 4. Base, Die #2 5. Collector, Die #2 6. Collector, Die #2 7. Collector, Die #1 8. Collector, Die #1
STYLE 17: PIN 1. VCC 2. V2OUT 3. V1OUT 4. TXE 5. RXE 6. VEE 7. GND 8. ACC	STYLE 18: PIN 1. Anode 2. Anode 3. Source 4. Gate 5. Drain 6. Drain 7. Cathode 8. Cathode	STYLE 19: PIN 1. Source 1 2. Gate 1 3. Source 2 4. Gate 2 5. Drain 2 6. Mirror 2 7. Drain 1 8. Mirror 1	STYLE 20: PIN 1. Source (N) 2. Gate (N) 3. Source (P) 4. Gate (P) 5. Drain 6. Drain 7. Drain 8. Drain
STYLE 21: PIN 1. Cathode 1 2. Cathode 2 3. Cathode 3 4. Cathode 4 5. Cathode 5 6. Common Anode 7. Common Anode 8. Cathode 6	STYLE 22: PIN 1. I/O Line 1 2. Common Cathode/VCC 3. Common Cathode/VCC 4. I/O Line 3 5. Common Anode/GND 6. I/O Line 4 7. I/O Line 5 8. Common Anode/GND	STYLE 23: PIN 1. Line 1 IN 2. Common Anode/GND 3. Common Anode/GND 4. Line 2 IN 5. Line 2 OUT 6. Common Anode/GND 7. Common Anode/GND 8. Line 1 OUT	STYLE 24: PIN 1. Base 2. Emitter 3. Collector/Anode 4. Collector/Anode 5. Cathode 6. Cathode 7. Collector/Anode 8. Collector/Anode
STYLE 25: PIN 1. VIN 2. N/C 3. REXT 4. GND 5. IOUT 6. IOUT 7. IOUT 8. IOUT	STYLE 26: PIN 1. GND 2. dv/dt 3. Enable 4. ILIMIT 5. Source 6. Source 7. Source 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. Source 6. Source 7. Source 8. Drain	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBUCK 7. VBUCK 8. VIN
STYLE 29: PIN 1. Base, Die #1 2. Emitter, #1 3. Base, #2 4. Emitter, #2 5. Collector, #2 6. Collector, #2 7. Collector, #1 8. Collector, #1	STYLE 30: PIN 1. Drain 1 2. Drain 1 3. Gate 2 4. Source 2 5. Source 1/Drain 2 6. Source 1/Drain 2 7. Source 1/Drain 2 8. Gate 1		

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MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

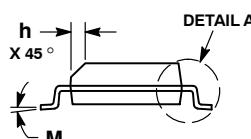
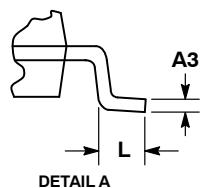
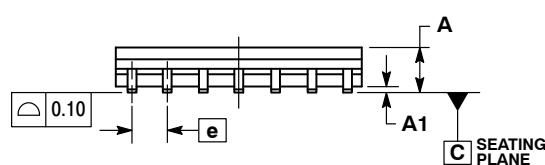
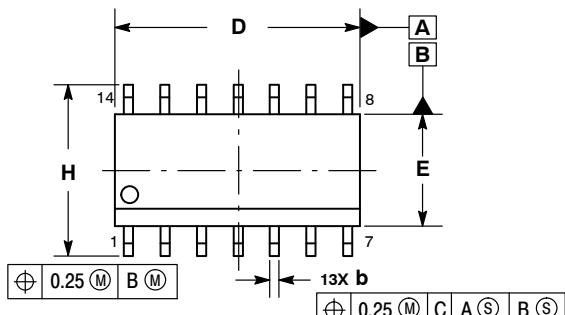
onsemiTM



SCALE 1:1

SOIC-14 NB
CASE 751A-03
ISSUE L

DATE 03 FEB 2016

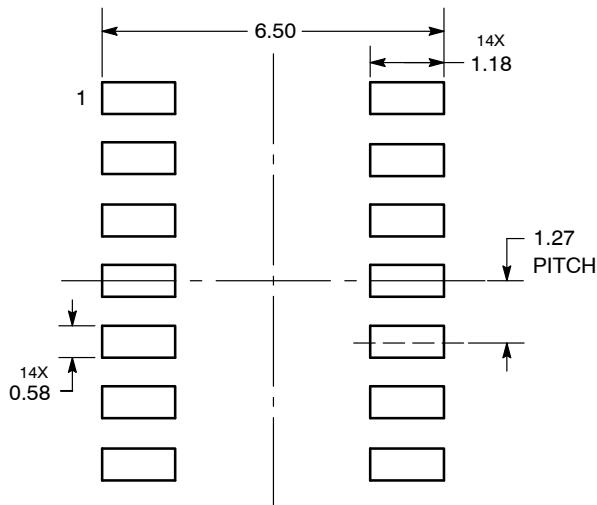


NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT MAXIMUM MATERIAL CONDITION.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
A3	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
M	0 °	7 °	0 °	7 °

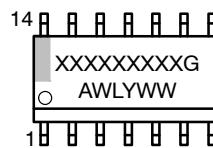
SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

**GENERIC
MARKING DIAGRAM***



XXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
Y = Year
WW = Work Week
G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

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SOIC-14
CASE 751A-03
ISSUE L

DATE 03 FEB 2016

STYLE 1:
PIN 1. COMMON CATHODE
2. ANODE/CATHODE
3. ANODE/CATHODE
4. NO CONNECTION
5. ANODE/CATHODE
6. NO CONNECTION
7. ANODE/CATHODE
8. ANODE/CATHODE
9. ANODE/CATHODE
10. NO CONNECTION
11. ANODE/CATHODE
12. ANODE/CATHODE
13. NO CONNECTION
14. COMMON ANODE

STYLE 2:
CANCELLED

STYLE 3:
PIN 1. NO CONNECTION
2. ANODE
3. ANODE
4. NO CONNECTION
5. ANODE
6. NO CONNECTION
7. ANODE
8. ANODE
9. ANODE
10. NO CONNECTION
11. ANODE
12. ANODE
13. NO CONNECTION
14. COMMON CATHODE

STYLE 4:
PIN 1. NO CONNECTION
2. CATHODE
3. CATHODE
4. NO CONNECTION
5. CATHODE
6. NO CONNECTION
7. CATHODE
8. CATHODE
9. CATHODE
10. NO CONNECTION
11. CATHODE
12. CATHODE
13. NO CONNECTION
14. COMMON ANODE

STYLE 5:
PIN 1. COMMON CATHODE
2. ANODE/CATHODE
3. ANODE/CATHODE
4. ANODE/CATHODE
5. ANODE/CATHODE
6. NO CONNECTION
7. COMMON ANODE
8. COMMON CATHODE
9. ANODE/CATHODE
10. ANODE/CATHODE
11. ANODE/CATHODE
12. ANODE/CATHODE
13. NO CONNECTION
14. COMMON ANODE

STYLE 6:
PIN 1. CATHODE
2. CATHODE
3. CATHODE
4. CATHODE
5. CATHODE
6. CATHODE
7. CATHODE
8. ANODE
9. ANODE
10. ANODE
11. ANODE
12. ANODE
13. ANODE
14. ANODE

STYLE 7:
PIN 1. ANODE/CATHODE
2. COMMON ANODE
3. COMMON CATHODE
4. ANODE/CATHODE
5. ANODE/CATHODE
6. ANODE/CATHODE
7. ANODE/CATHODE
8. ANODE/CATHODE
9. ANODE/CATHODE
10. ANODE/CATHODE
11. COMMON CATHODE
12. COMMON ANODE
13. ANODE/CATHODE
14. ANODE/CATHODE

STYLE 8:
PIN 1. COMMON CATHODE
2. ANODE/CATHODE
3. ANODE/CATHODE
4. NO CONNECTION
5. ANODE/CATHODE
6. ANODE/CATHODE
7. COMMON ANODE
8. COMMON ANODE
9. ANODE/CATHODE
10. ANODE/CATHODE
11. NO CONNECTION
12. ANODE/CATHODE
13. ANODE/CATHODE
14. COMMON CATHODE

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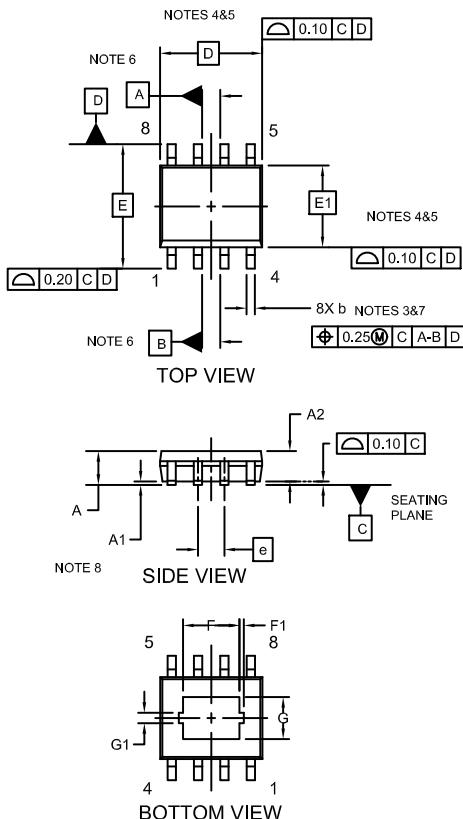
MECHANICAL CASE OUTLINE

PACKAGE DIMENSIONS

ON Semiconductor®



SCALE 1:1

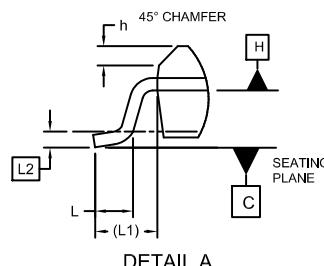


SOIC-8 EP CASE 751AC ISSUE D

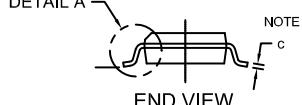
DATE 02 APR 2019

NOTES:

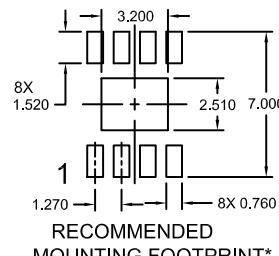
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.004 IN EXCESS OF MAXIMUM MATERIAL CONDITION.
4. DIMENSION D DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 PER SIDE. DIMENSION E1 DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.010 mm PER SIDE.
5. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM. DIMENSIONS D AND E1 ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
6. DATUMS A AND B ARE TO BE DETERMINED AT DATUM H.
7. DIMENSIONS b AND c APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10 TO 0.25 FROM THE LEAD TIP.
8. A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.



DETAIL A



END VIEW

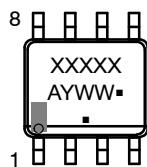


RECOMMENDED
MOUNTING FOOTPRINT*

DIM	MILLIMETERS		
	MIN.	NOM.	MAX.
A	1.35	1.55	1.75
A1	--	0.05	0.10
A2	1.35	1.50	1.65
b	0.31	0.41	0.51
c	0.17	0.21	0.23
D	4.90 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	1.27 BSC		
F	2.24	2.72	3.20
F1	0.15	0.20	0.25
G	1.55	2.03	2.51
G1	0.41	0.46	0.51
h	0.25	0.38	0.50
L	0.40	0.84	1.27
L1	1.04 REF		
L2	0.25 REF		
Ø	0°	4°	8°

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D."

GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
▪ = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present and may be in either location. Some products may not follow the Generic Marking.

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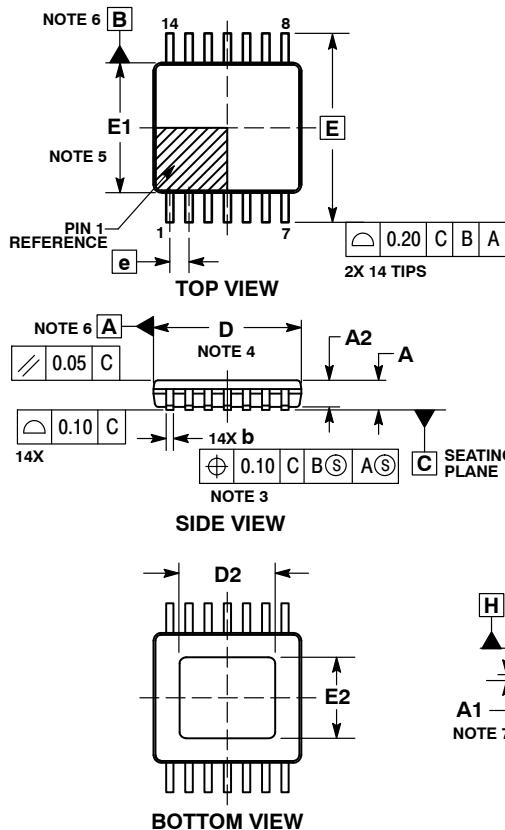
MECHANICAL CASE OUTLINE

PACKAGE DIMENSIONS

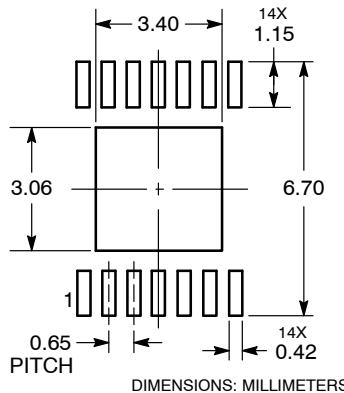
ON Semiconductor®



SCALE 1:1



RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

TSSOP-14 EP CASE 948AW ISSUE C

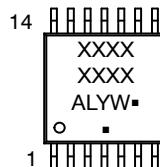
DATE 09 OCT 2012

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.07 mm MAX. AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADUS OF THE FOOT. MINIMUM SPACE BETWEEN PROTRUSION AND ADJACENT LEAD IS 0.07.
4. DIMENSION D DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 mm PER SIDE. DIMENSION D IS DETERMINED AT DATUM H.
5. DIMENSION E1 DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSIONS. INTERLEAD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.25 mm PER SIDE. DIMENSION E1 IS DETERMINED AT DATUM H.
6. DATUMS A AND B ARE DETERMINED AT DATUM H.
7. A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
8. SECTION B-B TO BE DETERMINED AT 0.10 TO 0.25 mm FROM THE LEAD TIP.

DIM	MILLIMETERS	
	MIN	MAX
A	-----	1.20
A1	0.05	0.15
A2	0.80	1.05
b	0.19	0.30
b1	0.19	0.25
c	0.09	0.20
c1	0.09	0.16
D	4.90	5.10
D2	3.09	3.62
E	6.40 BSC	
E1	4.30	4.50
E2	2.69	3.22
e	0.65 BSC	
L	0.45	0.75
L2	0.25 BSC	
M	0 °	8 °

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code

A = Assembly Location

L = Wafer Lot

Y = Year

W = Work Week

▪ = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present.

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DESCRIPTION:	TSSOP-14 EP, 5.0X4.4	PAGE 1 OF 1

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